



*IBIS Summit 2005*

# **IBIS Power/Ground Modeling of LSI Core Logic with High-Pin Count Package for EMI and PI**

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**\*\*NEC Production Technology Laboratories**

# **Outlines**

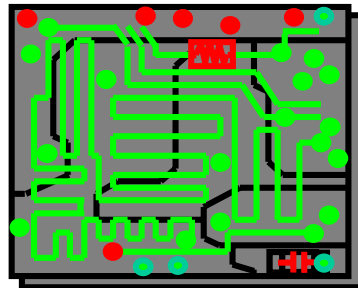
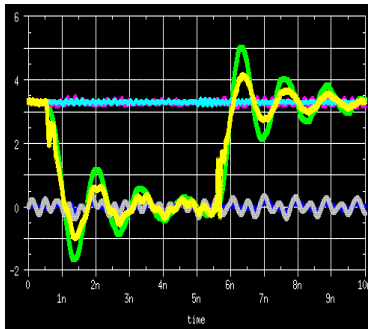
- 1. Introduction**
- 2. Modeling of Core Logic Power/Ground for EMI Simulation**
- 3. Modeling of High-Pin Count Package**
- 4. Conclusion**

# **1. Introduction**

# PI and EMI Simulation

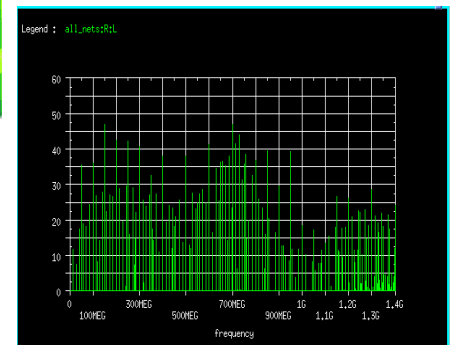
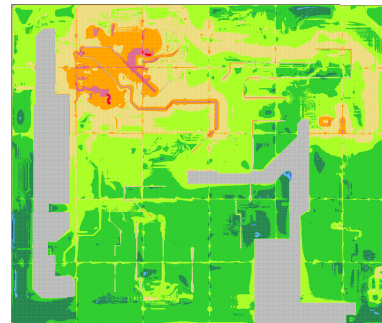
## PI

Power Integrity



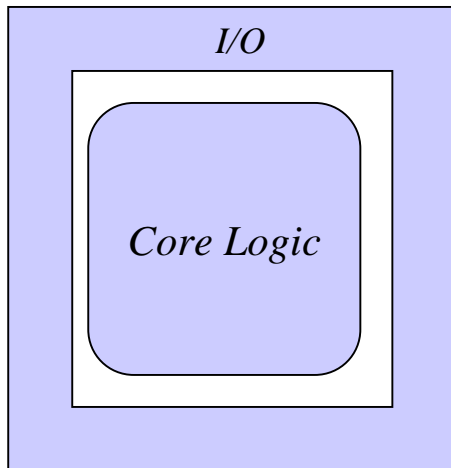
## EMI

Electromagnetic Interference



# Two Types of LSIs

## *LSI for Digital Consumer/Auto Mobile*

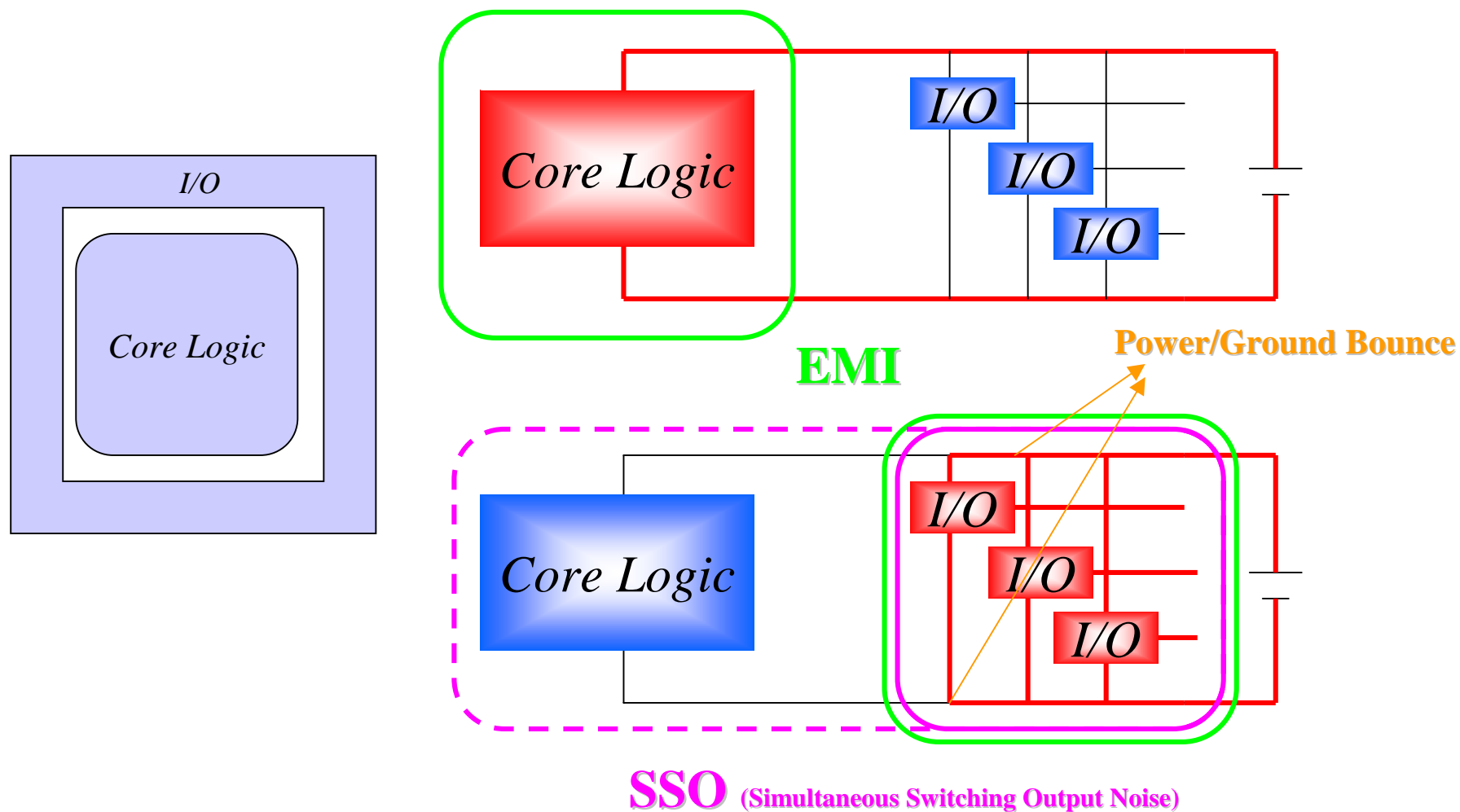


|                   | <i>Total Power/Current</i> | <i>Clock Freq</i> | <i>Voltage</i> |
|-------------------|----------------------------|-------------------|----------------|
| <i>Core Logic</i> | <b>High</b>                | <b>High</b>       | <b>Low</b>     |
| <i>I/O</i>        | <i>Low</i>                 | <i>Low</i>        | <i>High</i>    |

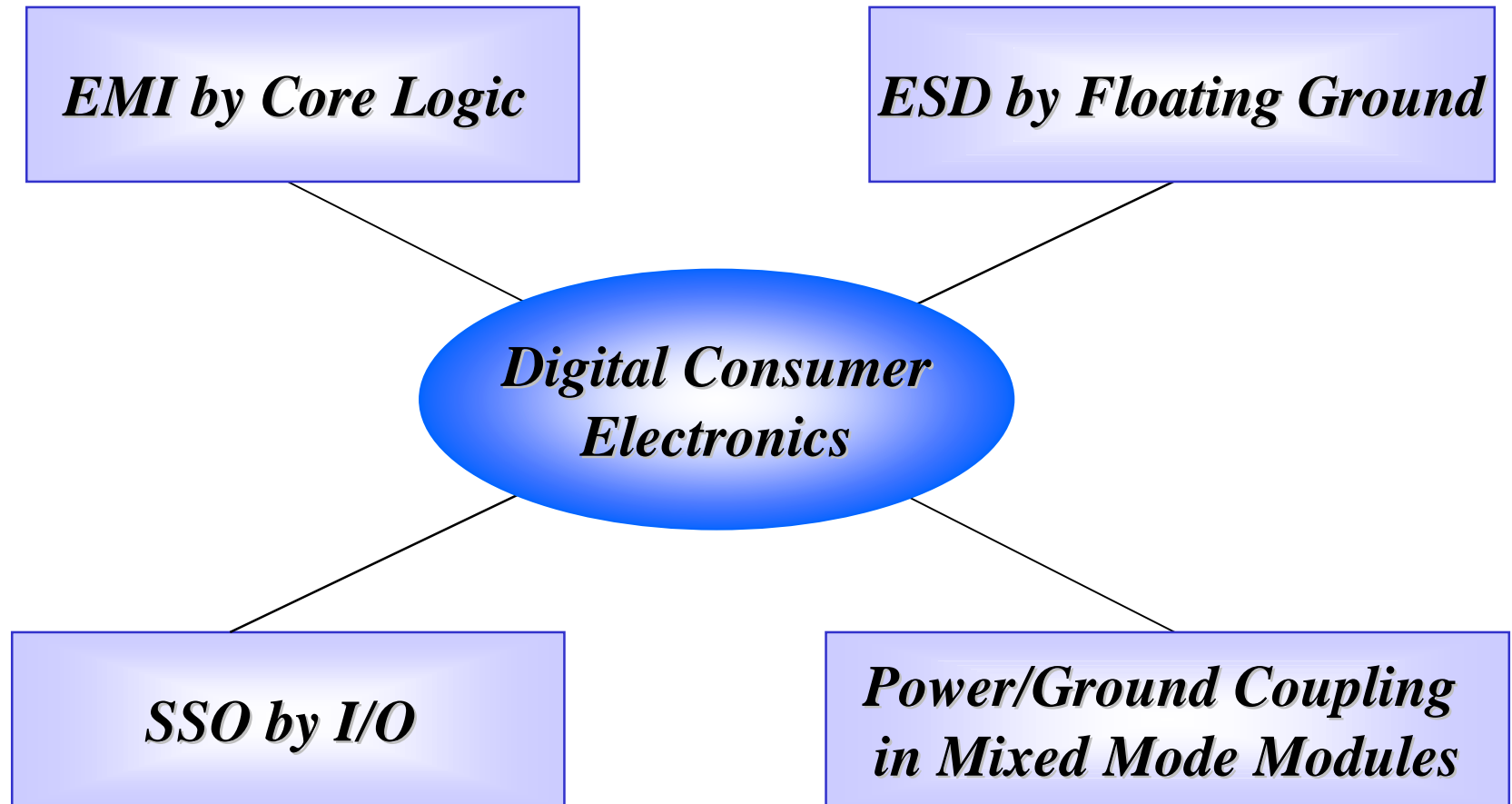
## *Driver IC*

|                   | <i>Total Power/Current</i> | <i>Clock Freq</i> | <i>Voltage</i> |
|-------------------|----------------------------|-------------------|----------------|
| <i>Core Logic</i> | <i>Low</i>                 | <i>Same/High</i>  | <i>Low</i>     |
| <b><i>I/O</i></b> | <b>High</b>                | <b>Low</b>        | <b>High</b>    |

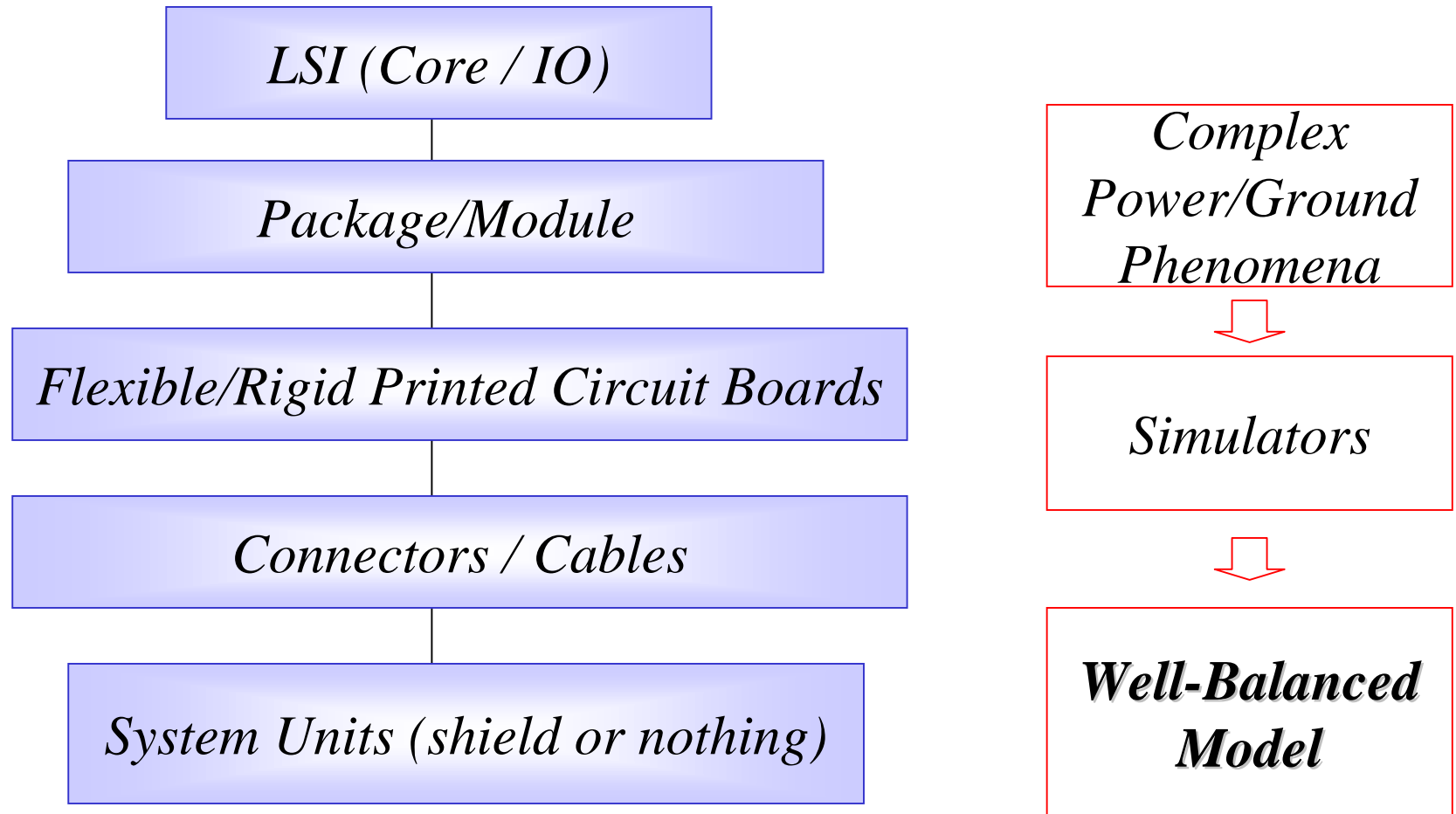
# Dominant Currents



# EMC in Digital Consumer Electronics



# Non-Ideal Ground at Various Levels





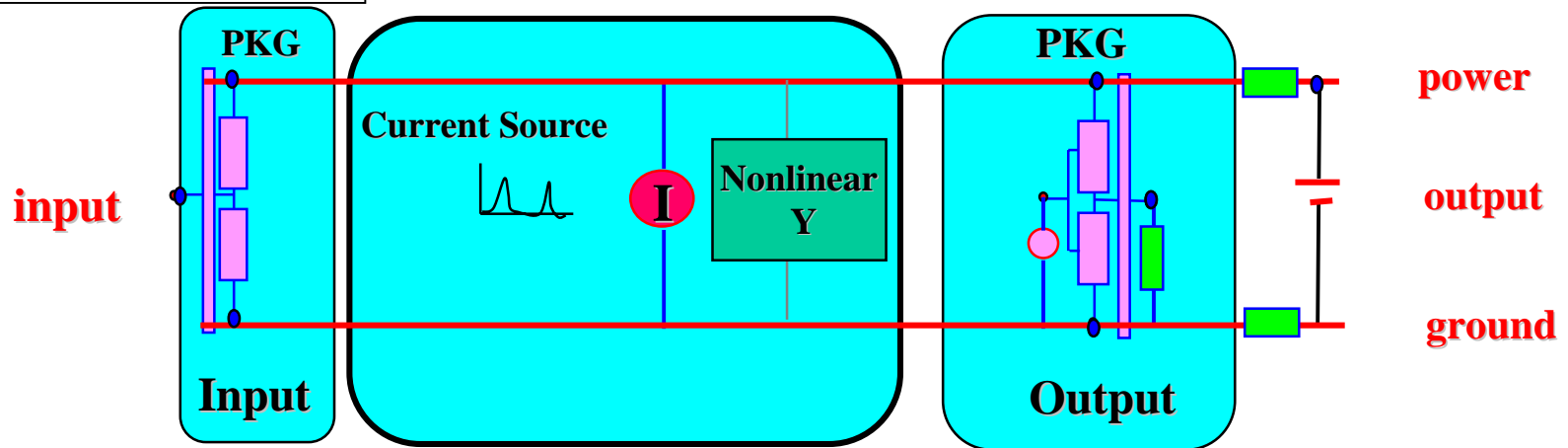
## **2. Modeling of Core Logic Power/Ground for EMI Simulation**

# System LSI for Digital Consumer Electronics

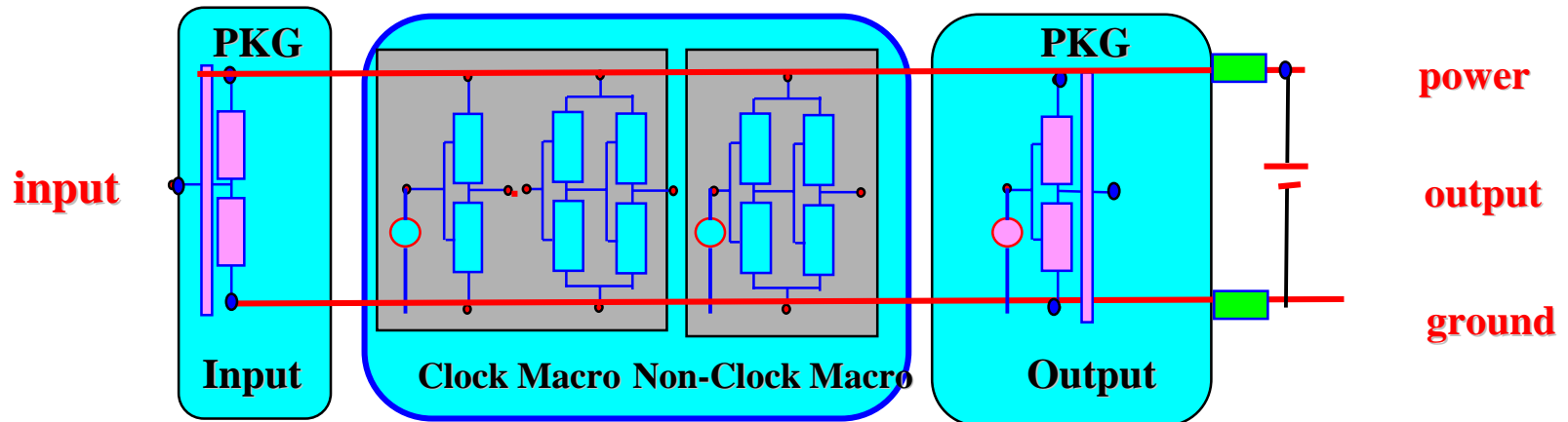
|                   | <i>Voltage</i> | <i>Current</i> | <i>Clock Frequency</i> |
|-------------------|----------------|----------------|------------------------|
| <i>Core Logic</i> | <i>1.2V</i>    | <i>2.5A</i>    | <i>96MHz</i>           |
|                   | <i>1.8V</i>    | <i>0.2A</i>    | <i>96MHz</i>           |
|                   | <i>2.5V</i>    | <i>0.5A</i>    | <i>96MHz</i>           |
| <i>I/O</i>        | <i>3.3V</i>    | <i>0.3A</i>    | <i>48MHz</i>           |

# Methods of Extraction of Core Logic Model for EMI

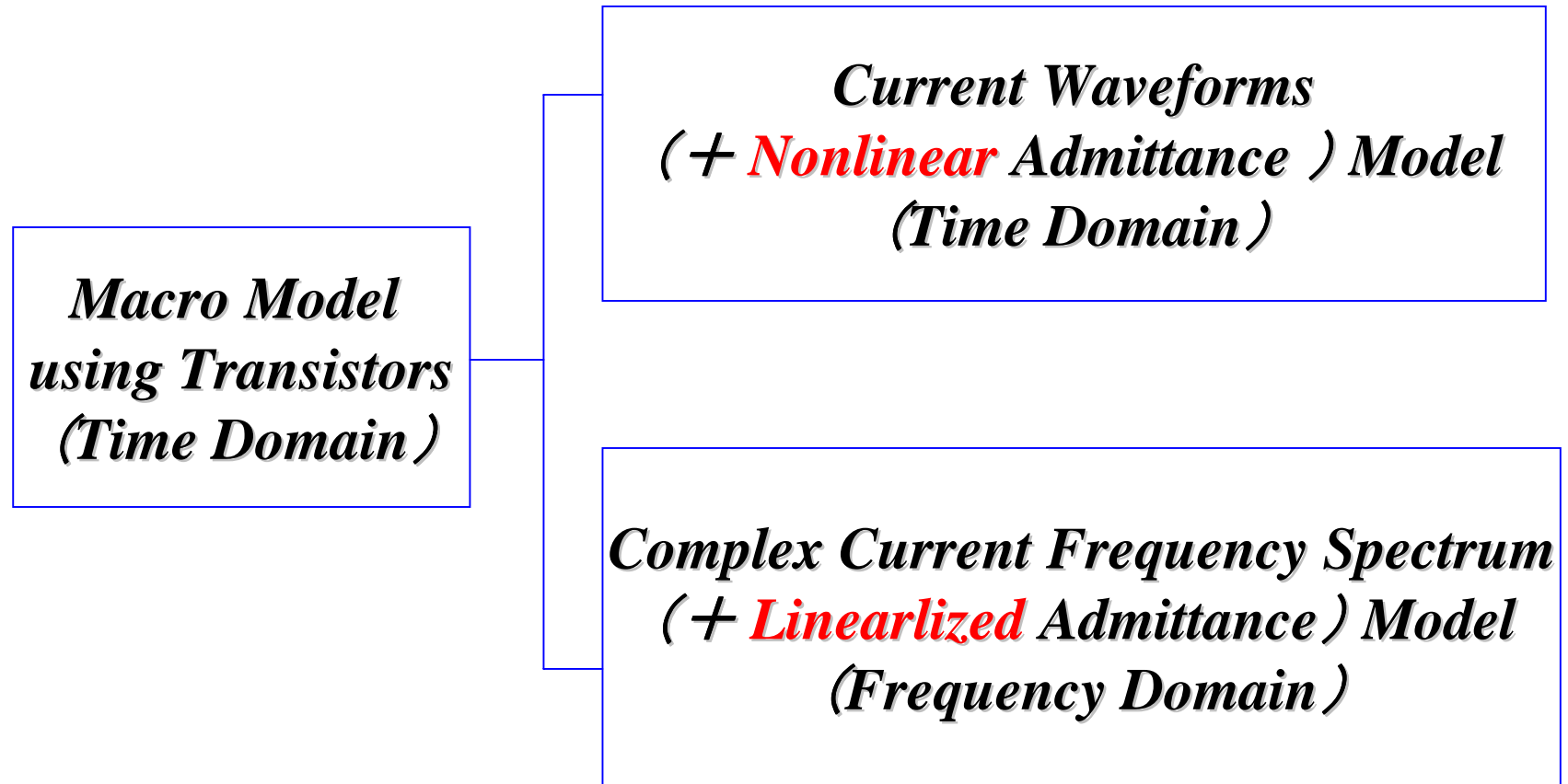
## By Measurement



## By CAD



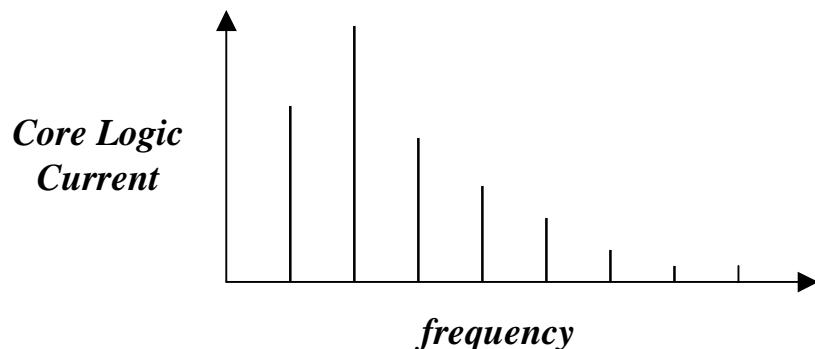
# Three Types of Core Logic Model for EMI



**+ Power/Ground Pattern on Chip and Package Model**

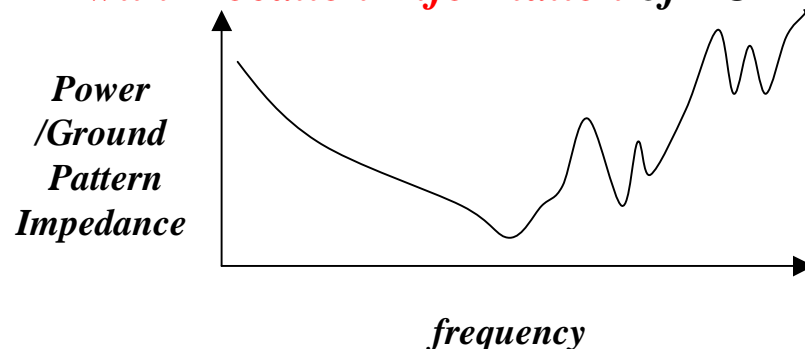
# EMI Simulation using Frequency Domain Model

*Equivalent Circuit in Frequency Domain*



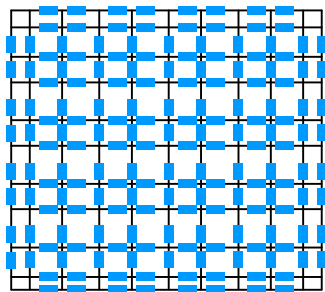
+

*Equivalent Circuit in Frequency Domain  
with Location Information of PCB*

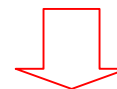


| Freq   | I(real) | I(imag) | Admittance<br>Equivalent<br>Circuit<br>Or<br>Frequency<br>Dependent<br>Admittance |
|--------|---------|---------|---|
| 96MHz  | 40mA    | -50uA   |   |
| 192MHz | 80mA    | 200uA   |   |
| 288MHz | 30mA    | -5mA    |   |
| ⋮      | ⋮       | ⋮       |   |

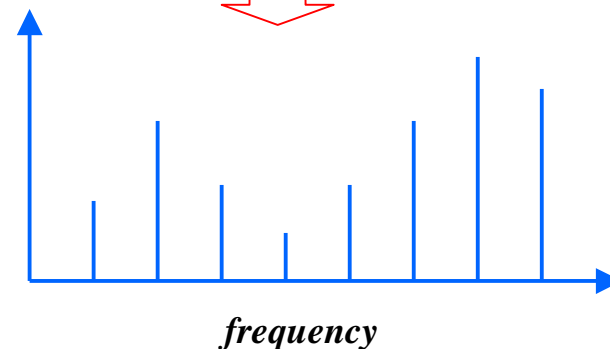
*LSI Power Grid Model*



*Current Distribution*

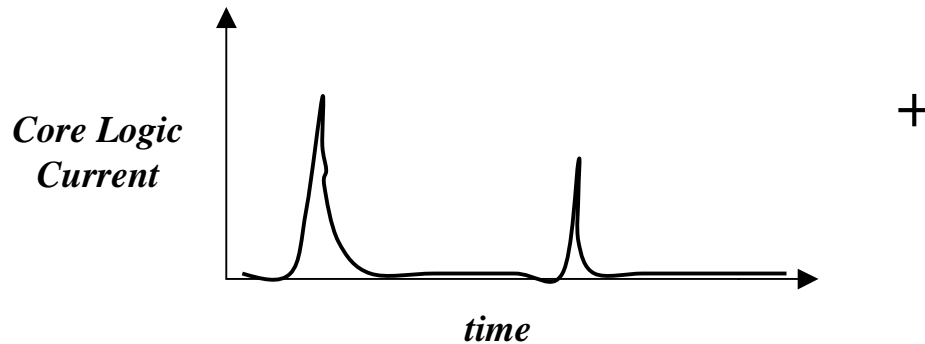


*Electric Field*

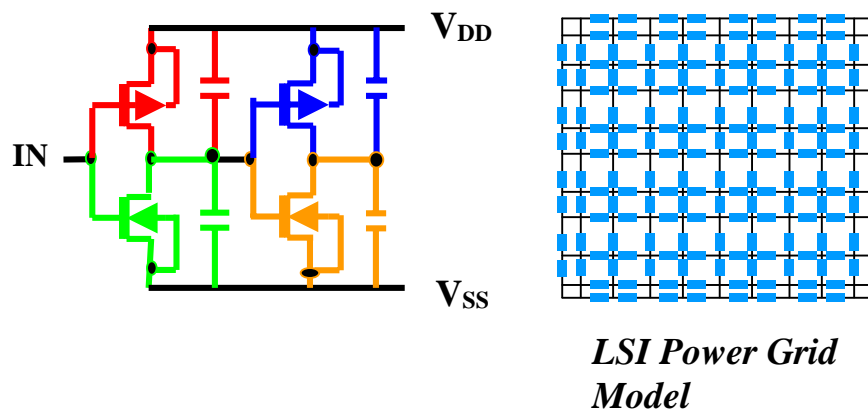


# EMI Simulation using Time Domain Model

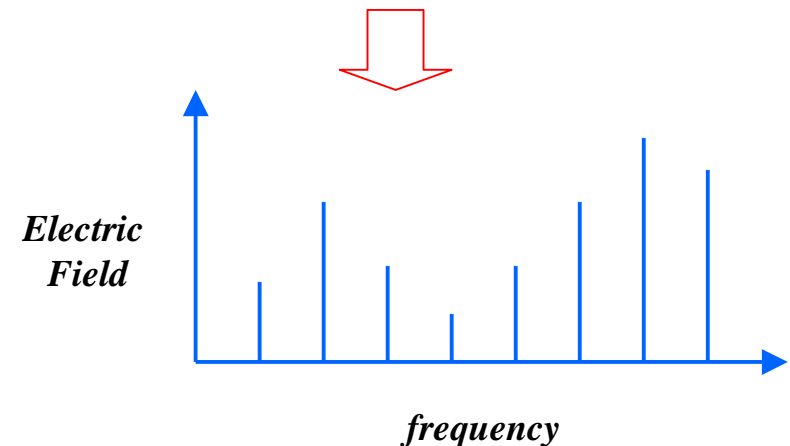
*Equivalent Circuit in Time Domain  
(Current waveforms are not necessary:  
Just switch Model between Voltage Source)*



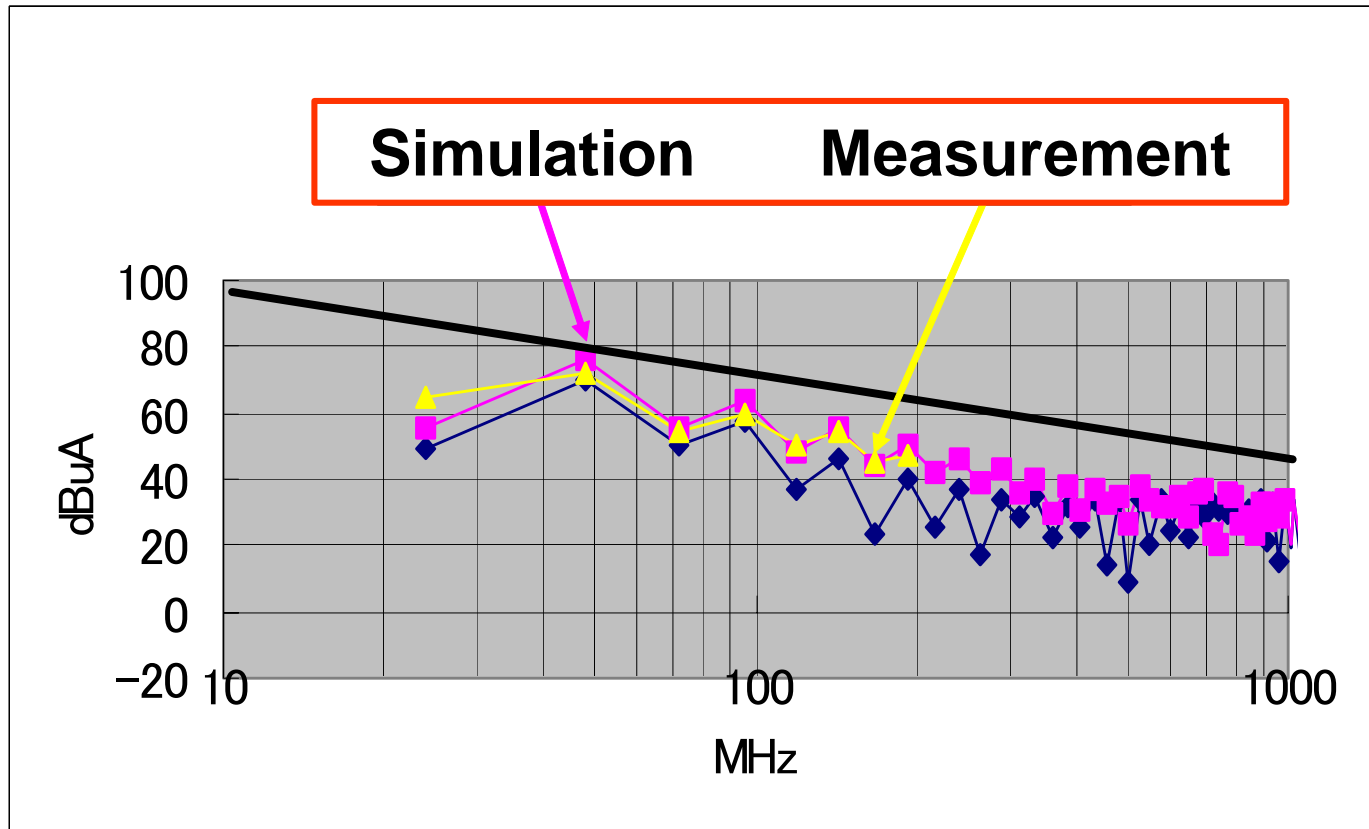
*Equivalent Circuit of Power and  
Ground Patterns in Time Domain  
with **Location Information** of PCB*



***Current Distribution  
(not current waveforms)***



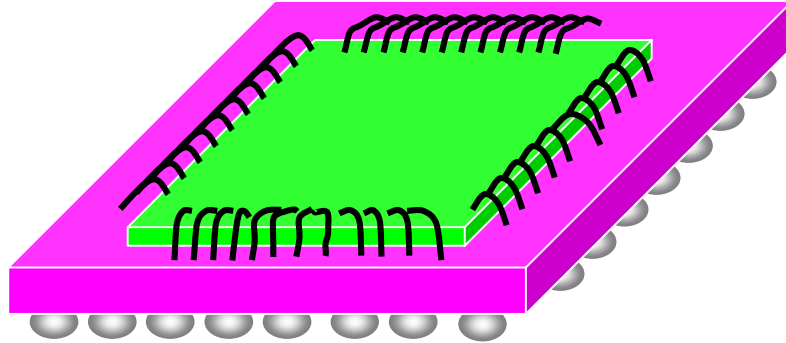
# Accuracy



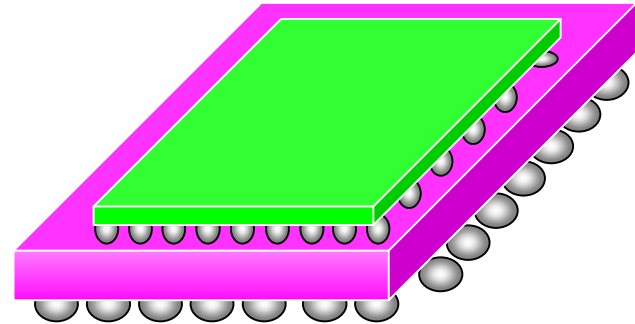
### **3. Modeling of High-Pin Count Package**



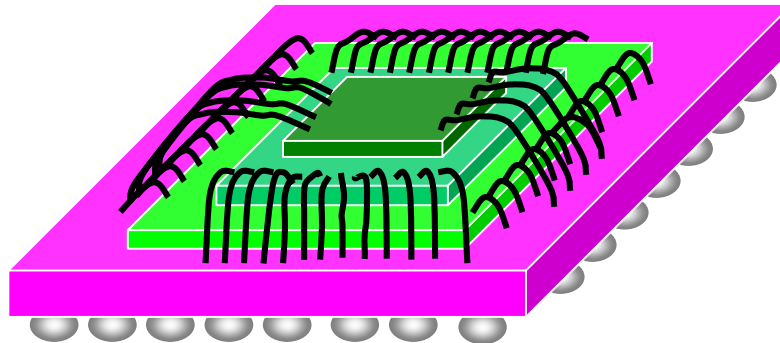
# Advanced IC Packages



**BGA/CSP (Bonding Wire)**

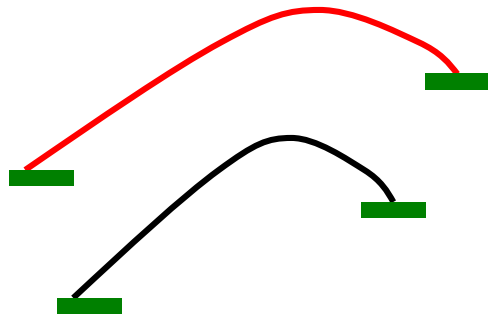


**BGA/CSP (Flip Chip)**



**SIP**

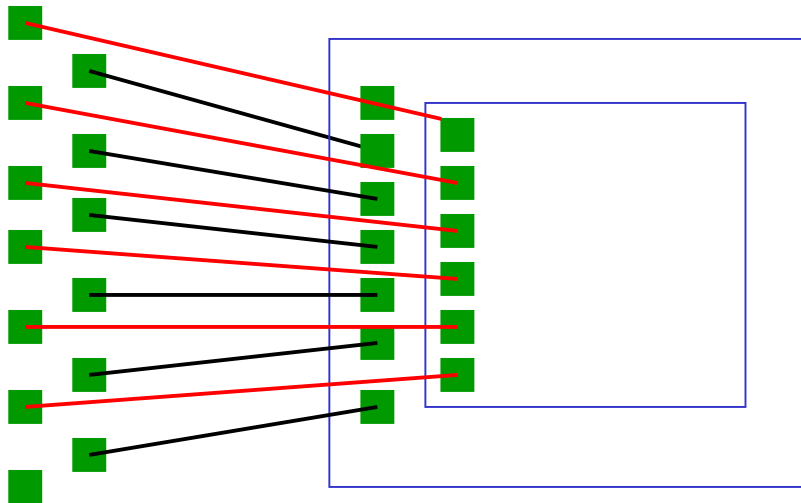
# Bonding Wires and Balls



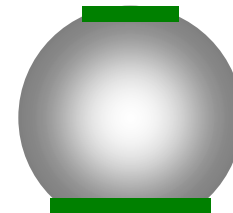
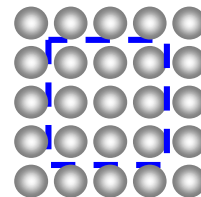
*Reference ground(s)*

*Coupling*

*Reference Ground*



*Pad on a chip/substrate*



*Pad on a substrate/PCB*



# **A Problem in IBIS IC Package Model**

**No Models of Power/Ground Pins**

**Only lead frame type package**

**Too Huge Model for Arbitrary Shape Power/Ground**

**Patterns with Many Pins**

**Partial Models**

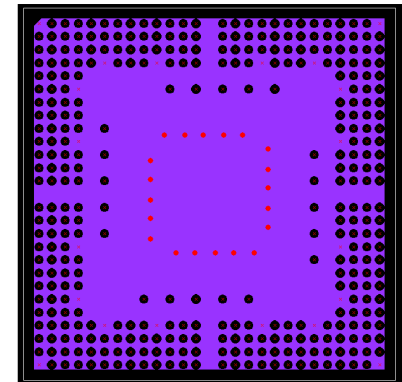
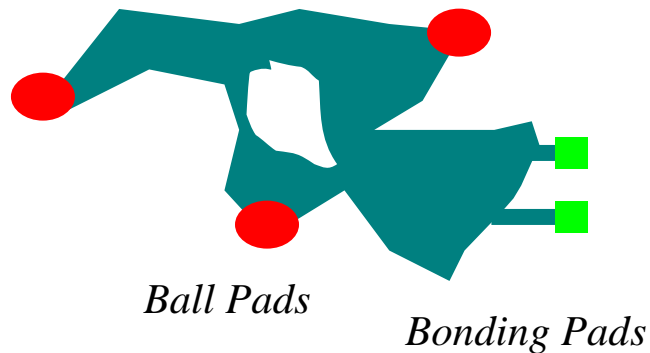
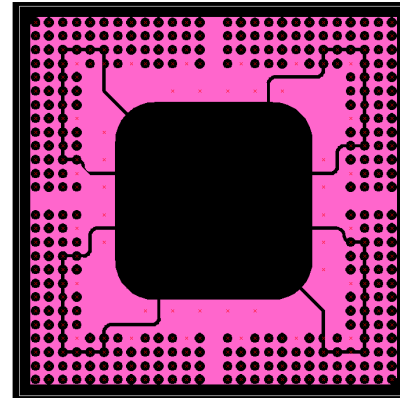
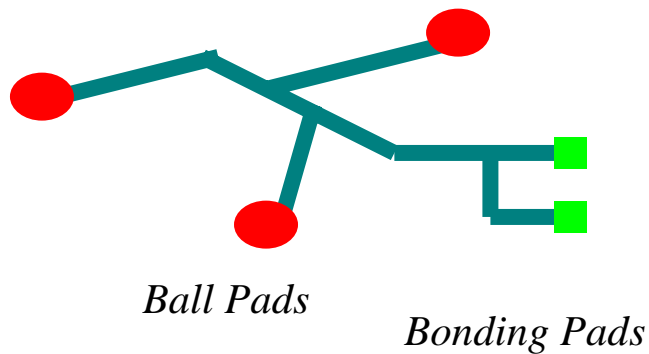
**Too complex to use for time domain analysis**

**Isolated Model from PCB and/or LSI chip**

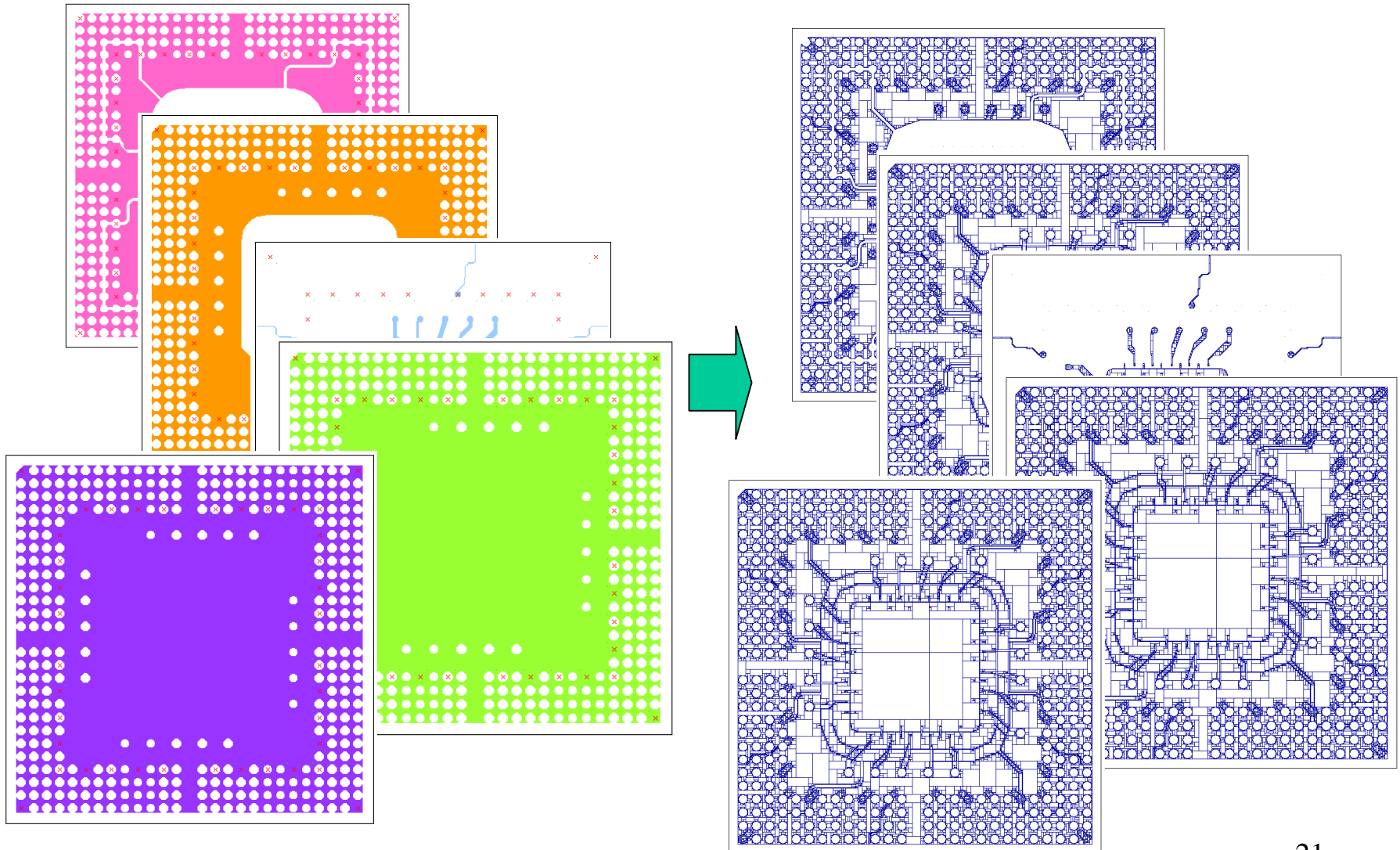
**(Some case needs to merge CAD DB)**

# Non-Ideal Power/Ground Needs ICM/IBIS 4.1

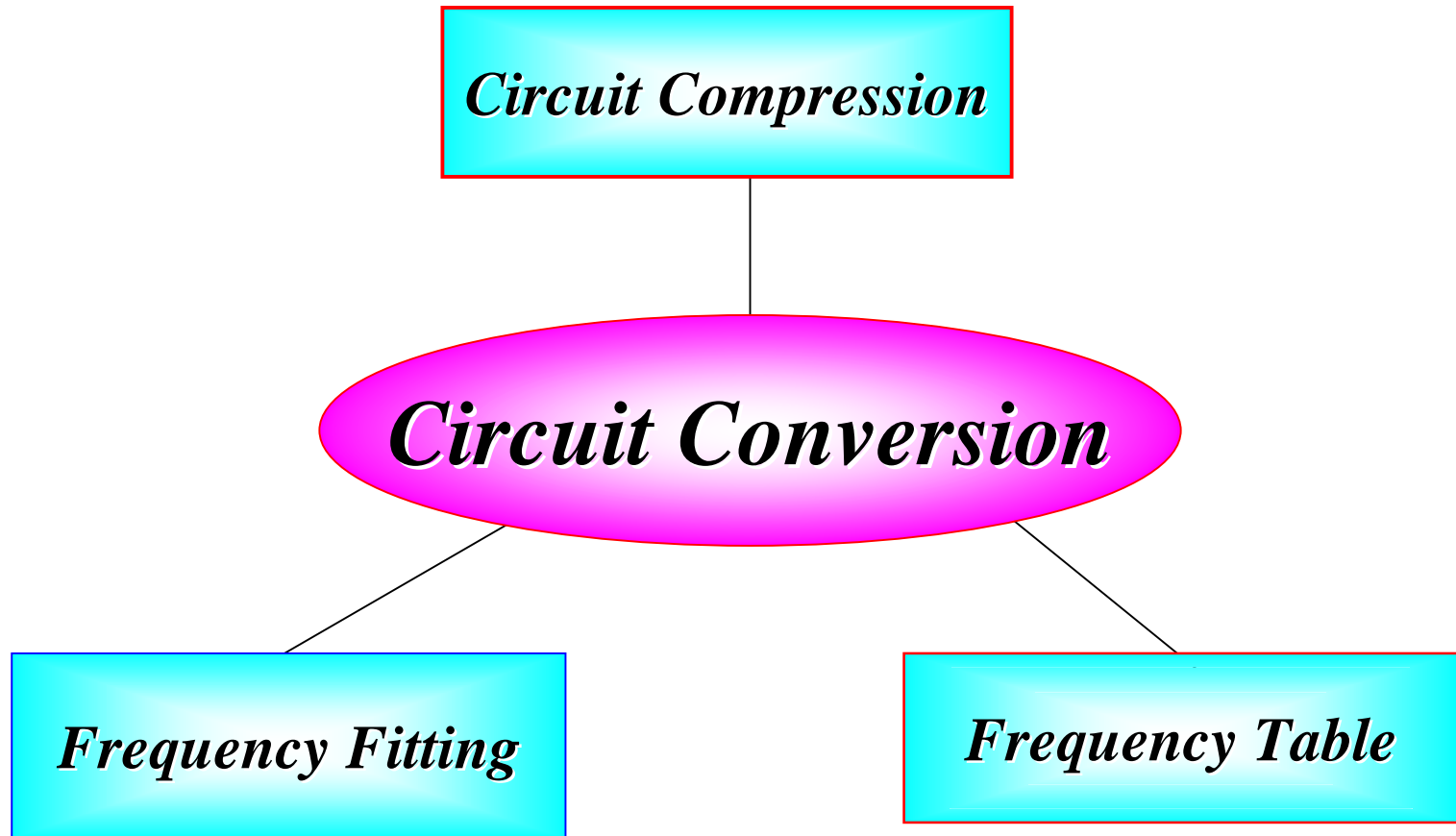
## *More than Two Terminals*



# Meshing Power and Ground

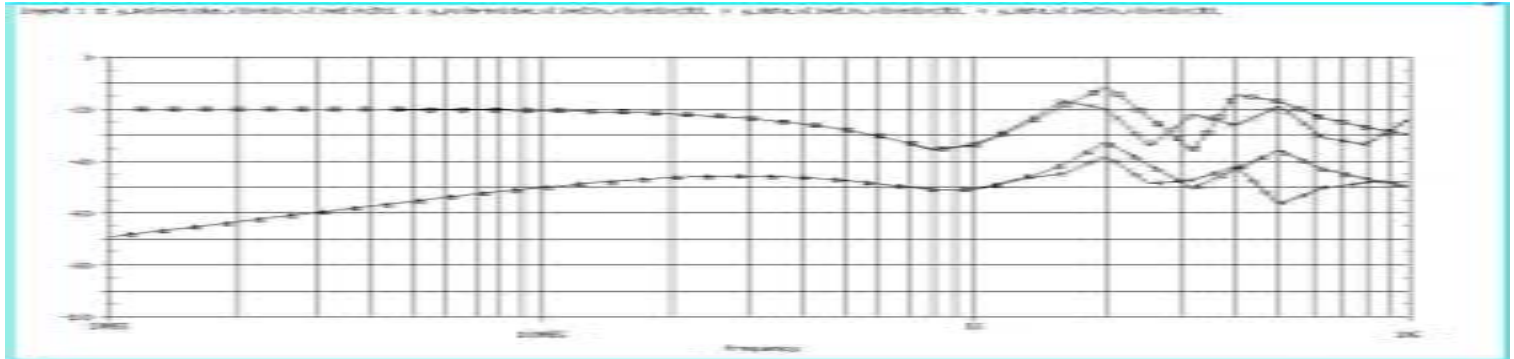


# Three Types of Model Order Reduction (MOR)

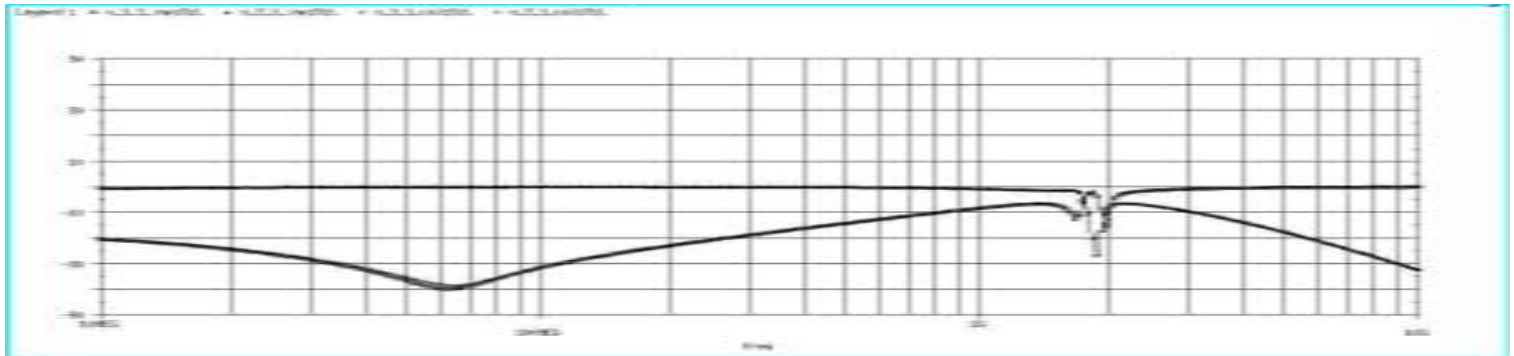


- **Three Types of Model Order Reduction (MOR)**

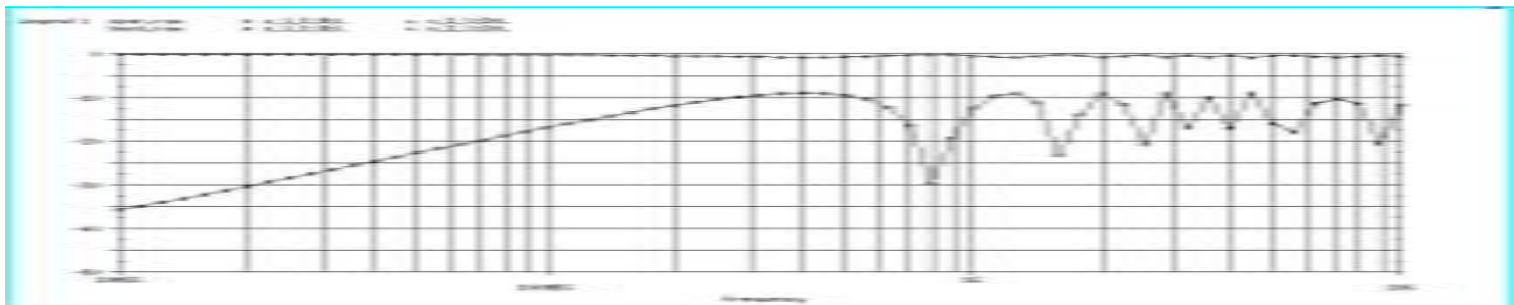
**Circuit  
Direct  
Compression**



**Frequency  
Fitting**



**Frequency Table  
(SPICE IFFT)**

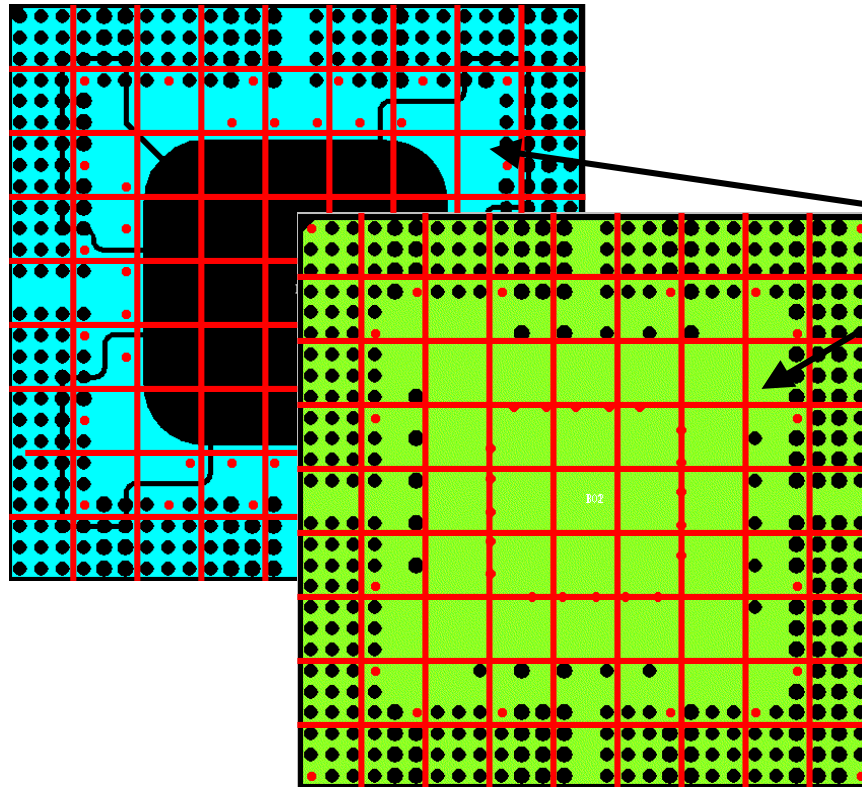


# Comparison of MOR

|  | <b>Circuit Direct<br/>Compression</b>                       | <b>Frequency Fitting</b>   | <b>Frequency Table</b>                                       |
|--|---|--|--|
| <b>Input Data</b>  | <b>Lumped Elements<br/>with no frequency<br/>dependency</b> | <b>N-port Parameters</b><br><br><b>(by Measurement or Field Solver,<br/>Linear Elements with frequency dependency)</b> |  |
| <b>Output Data</b>   | <b>G-element,<br/>Segmented<br/>Lumped Elements</b>         | <b>G-element<br/>(Polynomial)</b>  | <b>G-element<br/>(Frequency Table)</b>                       |
| <b>Stability with Nonlinear<br/>Devices in Time Domain</b> | <b>Stable<br/>Fast</b>                                      | <b>Unstable/Stable<br/>Fast</b>  | <b>Unstable / Slow<br/>Stable needs huge<br/>data points</b> |
| <b>Applications</b>  | <b>Need Circuit Data</b>                                    | <b>Short Structure<br/>Few Resonance</b>   | <b>Long Structure<br/>Many Resonance</b>                     |



# Needs Huge Computation to Make a Macro Model for High-Pin Count Power/Ground Patterns



## Double step MOR

Cell (I, J)

Each Cell model  
by MOR by Parallel  
Processing

+

Whole model  
by MOR

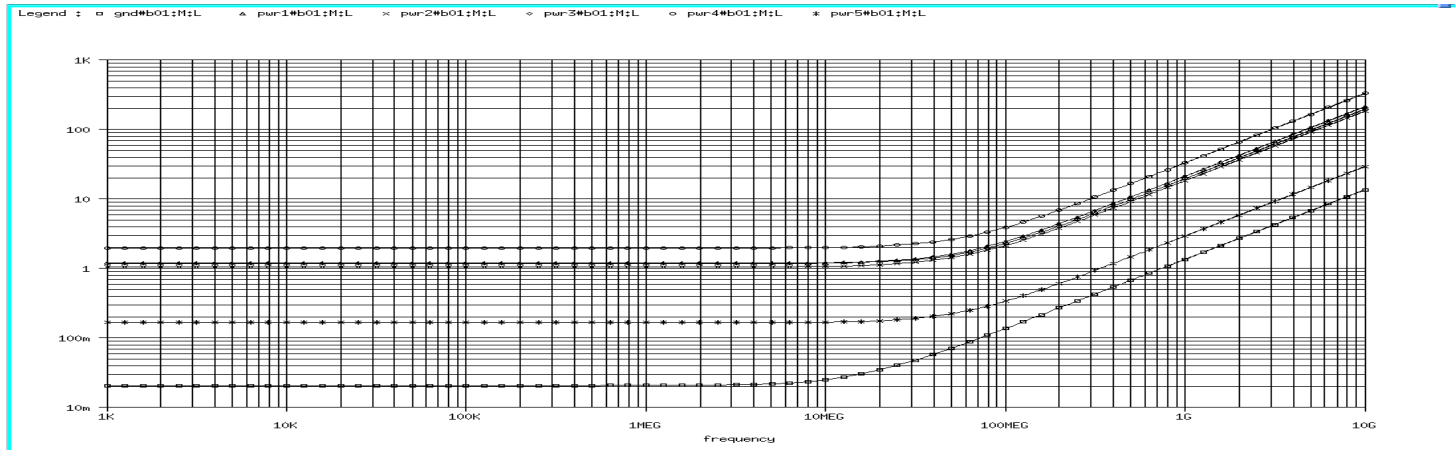
# Double Step MOR

|   | Modeling            |                          | Model Size       | Accuracy       | Modeling Time          | Comments           |
|---|---------------------|--------------------------|------------------|----------------|------------------------|--------------------|
|   | Cell Level          | Whole Level              |                  |                |                        |                    |
| 1 | ————                | PEEC                     | <i>Too Large</i> | <i>highest</i> | <i>Memory Overflow</i> | <i>Too large</i>   |
| 2 | PEEC                | ————                     | <i>Too Large</i> | <i>high</i>    | <i>Medium</i>          | <i>Too large</i>   |
| 3 | Circuit Compression | ————                     | <i>Large</i>     | <i>high</i>    | <i>Long</i>            | <i>Hard to use</i> |
| 4 | Circuit Compression | Circuit Compression      | <i>Small</i>     | <i>low</i>     | <i>Long</i>            | <i>Inaccurate</i>  |
| 5 | Circuit Compression | N-port Parameter Fitting | <i>Small</i>     | <i>medium</i>  | <i>Long</i>            | <i>Best</i>        |

# Impedance between Power and Ground

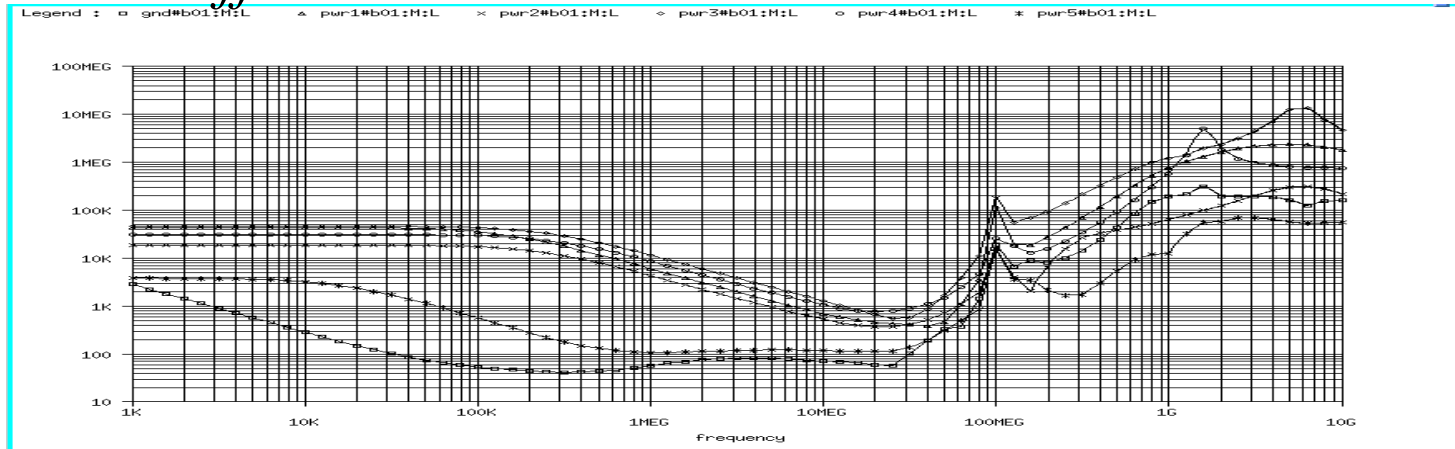
*Along the same net*

Impedance

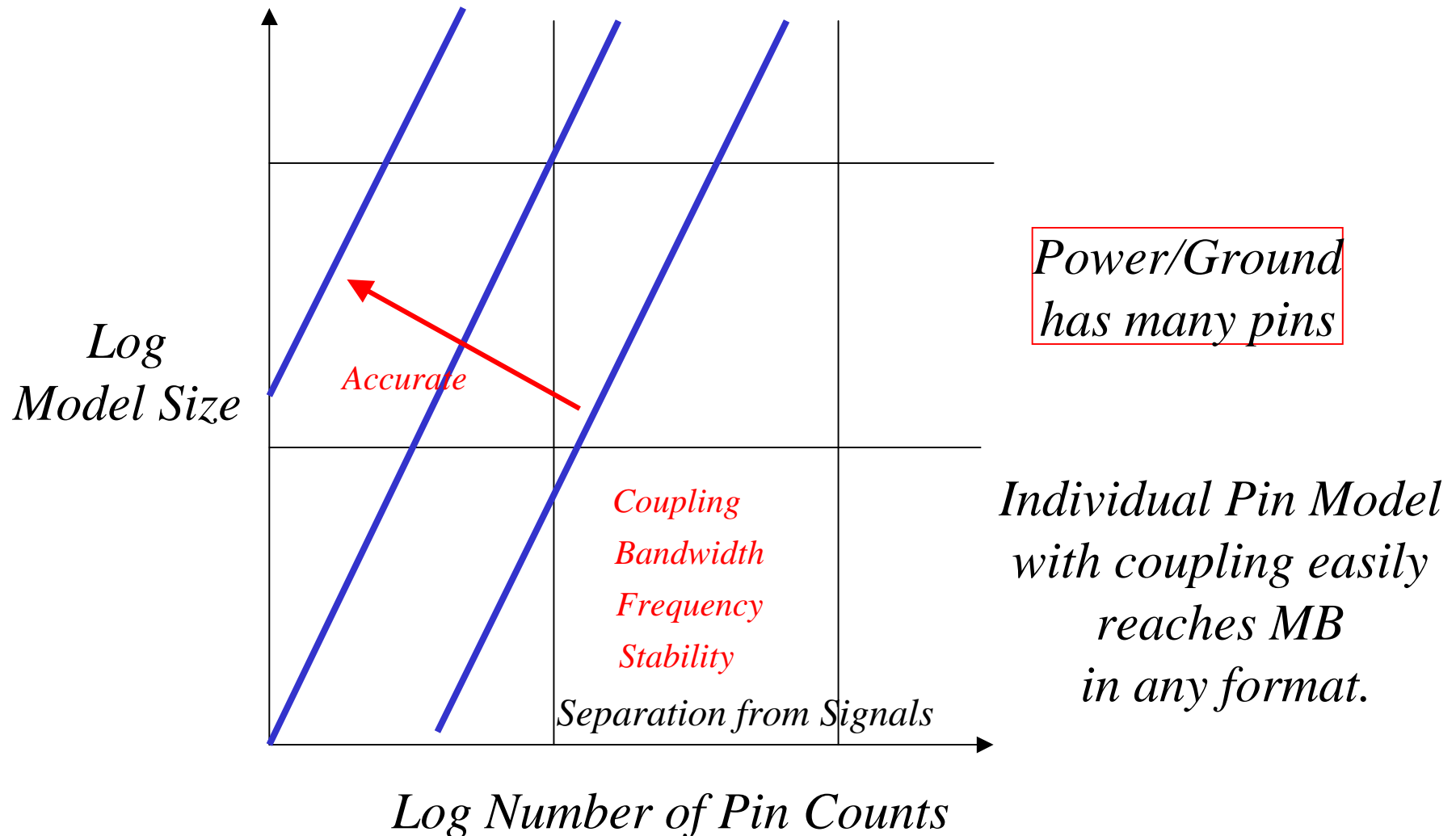


*Between the different nets*

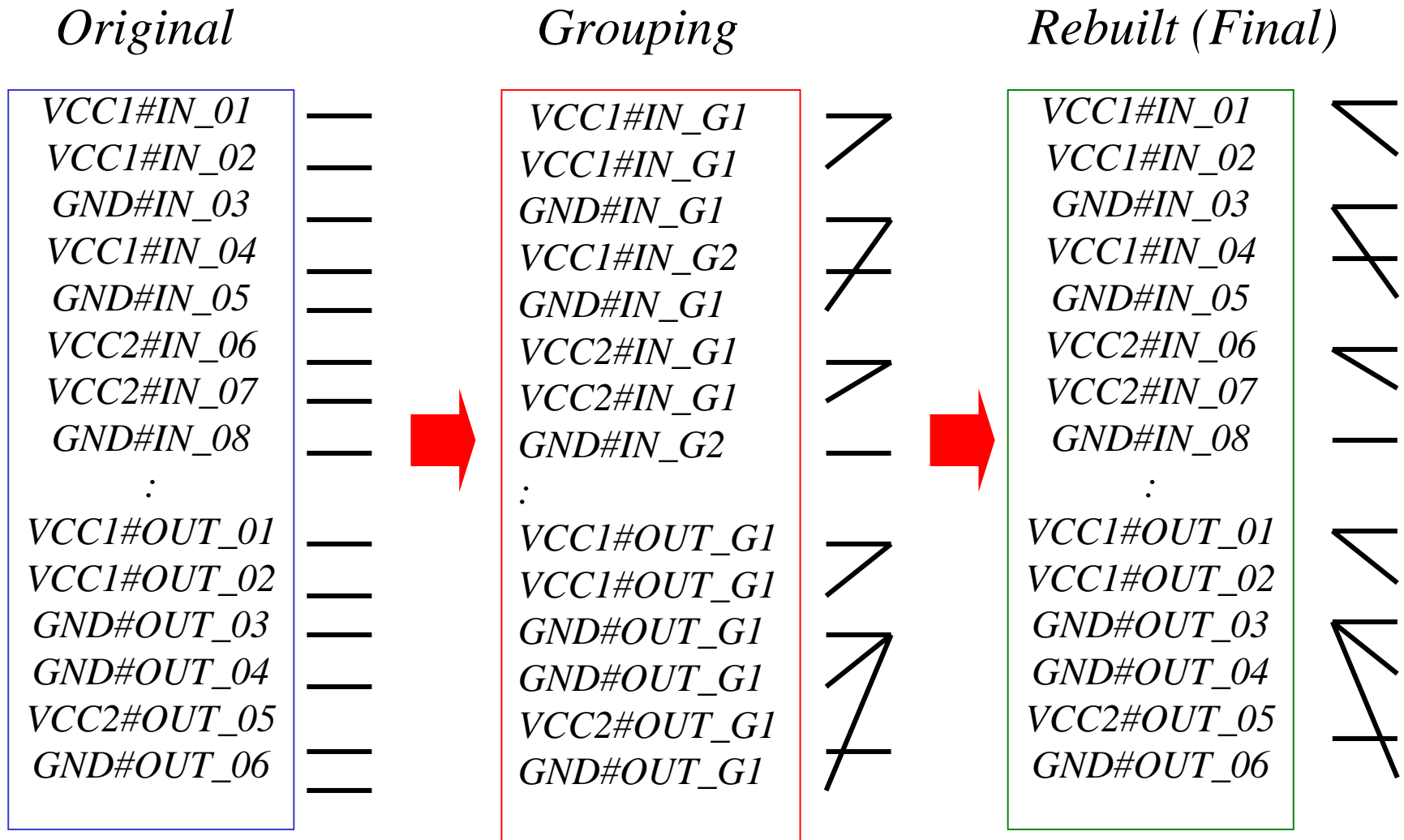
Impedance



# Still Needs a Smaller Model in Time Domain



# Grouping of closely located Pins may be needed



# Choice of Formats

***IBIS 4.1 / ICM 1.0 Formats***

***Applications***

***S-parameters***

***Time Domain***

***Lumped SPICE Networks***

***Frequency Domain***

***Coupled Transmission Line Networks***

## **4. Conclusion**

**Simple is best / Well-balanced Model**

**Different Models for SSO/Bounce/EMI**